



Shenzhen Tuofeng Semiconductor Technology Co., Ltd

N - CHANNEL ENHANCEMENT MODE POWER MOSFET

SGT MOS、低内阻、低结电容开关损耗小

TF030N06NG**• General Description**

The TF030N06NG uses advanced trench technology and design to provide excellent RDS(ON) withlowgate charge. It can be used in a wide variety of applications.

• Features

Advance device constructure

Low $R_{DS(ON)}$ to minimize conduction loss

Low Gate Charge for fast switching

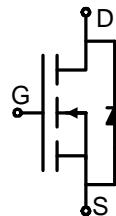
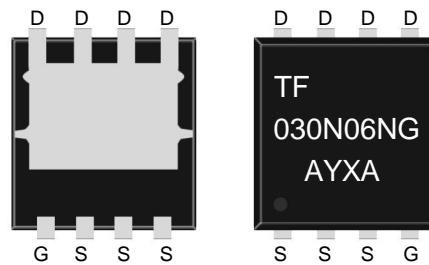
Low Thermal resistance

• Application

Synchronous Rectification for AC-DC/DC-DC

converter

Power Tools

• Product Summary $V_{DS} = 60V$ $I_D = 110A$ $R_{DS(ON)(10V\ typ)} = 3.3m\Omega$ $R_{DS(ON)(4.5V\ typ)} = 4.8m\Omega$ **PDFNWB5x6-8L****• Package Marking and Ordering Information:**

Part NO.	TF030N06NG
Marking1	030N06NG
Marking2	TF:tuofeng; AA:device code; Y:year code; X:Week
MOQ	5000

• Absolute Maximum Ratings ($T_C = 25^\circ C$)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	$I_D @ T_C = 25^\circ C$	110	A
	$I_D @ T_C = 75^\circ C$	77	A
	$I_D @ T_C = 100^\circ C$	66	A
Pulsed Drain Current ^①	I_{DM}	288	A
Total Power Dissipation	$P_D @ T_C = 25^\circ C$	55	W
Total Power Dissipation	$P_D @ T_A = 25^\circ C$	2.0	W
Operating Junction Temperature	T_J	-55 to 150	$^\circ C$
Storage Temperature	T_{STG}	-55 to 150	$^\circ C$
Single Pulse Avalanche Energy	E_{AS}	80	mJ



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N - CHANNEL ENHANCEMENT MODE POWER MOSFET**SGT MOS、低内阻、低结电容开关损耗小****TF030N06NG****Electrical Characteristics ($T_J = 25^\circ\text{C}$, unless otherwise noted)**

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	60	-	-	V
Gate-body Leakage Current	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$	-	-	± 100	nA
Zero Gate Voltage Drain Current $T_J=25^\circ\text{C}$	I_{DSS}	$V_{\text{DS}} = 58\text{V}, V_{\text{GS}} = 0\text{V}$	-	-	1	μA
$T_J=100^\circ\text{C}$			-	-	100	
Gate-Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.2	1.9	2.5	V
Drain-Source On-Resistance ⁴	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 20\text{A}$	-	3.3	5.0	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5\text{V}, I_D = 15\text{A}$	-	4.8	6.7	
Forward Transconductance ⁴	g_{fs}	$V_{\text{DS}} = 10\text{V}, I_D = 20\text{A}$	-	89	-	S
Dynamic Characteristics⁵						
Input Capacitance	C_{iss}	$V_{\text{DS}} = 30\text{V}, V_{\text{GS}} = 0\text{V}, f = 1\text{MHz}$	-	1990	-	pF
Output Capacitance	C_{oss}		-	735	-	
Reverse Transfer Capacitance	C_{rss}		-	42	-	
Gate Resistance	R_g	$f = 1\text{MHz}$	-	1.8	-	Ω
Switching Characteristics⁵						
Total Gate Charge	Q_g	$V_{\text{GS}} = 10\text{V}, V_{\text{DS}} = 30\text{V}, I_D = 20\text{A}$	-	35	-	nC
Gate-Source Charge	Q_{gs}		-	6.6	-	
Gate-Drain Charge	Q_{gd}		-	8.4	-	
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{GS}} = 10\text{V}, V_{\text{DD}} = 30\text{V}, R_G = 3\Omega, I_D = 20\text{A}$	-	9.4	-	ns
Rise Time	t_r		-	8.4	-	
Turn-Off Delay Time	$t_{\text{d(off)}}$		-	32.5	-	
Fall Time	t_f		-	12.5	-	
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 20\text{A}, dI/dt = 100\text{A}/\mu\text{s}$	-	50	-	ns
Body Diode Reverse Recovery Charge	Q_{rr}		-	20	-	nC
Drain-Source Body Diode Characteristics						
Diode Forward Voltage ⁴	V_{SD}	$I_S = 20\text{A}, V_{\text{GS}} = 0\text{V}$	-	-	1.2	V
Continuous Source Current	$T_C = 25^\circ\text{C}$	I_S	-	-	72	A

Notes:

1. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})} = 150^\circ\text{C}$
2. The EAS data shows Max. rating . The test condition is $V_{\text{DD}} = 25\text{V}, V_{\text{GS}} = 10\text{V}, L = 0.1\text{mH}, I_{\text{AS}} = 40\text{A}$.
3. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$.
5. This value is guaranteed by design hence it is not included in the production test.



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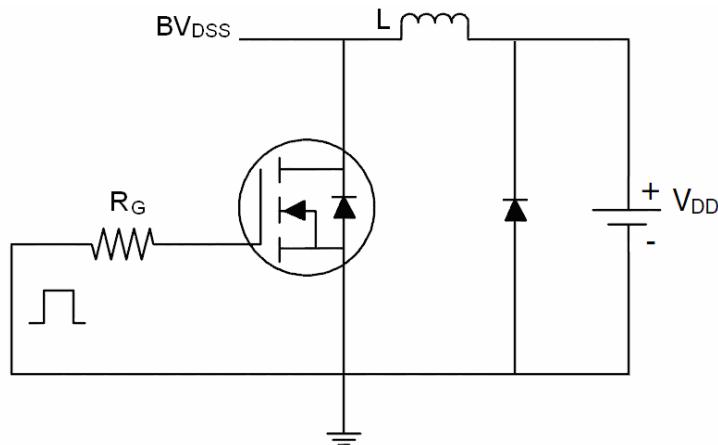
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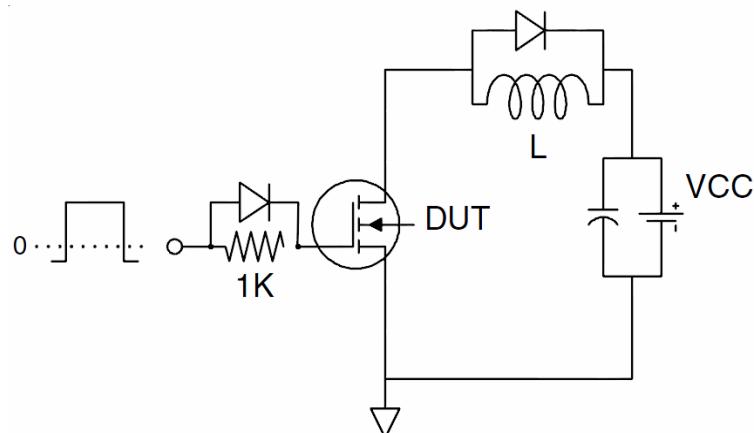
TF030N06NG

Test Circuit

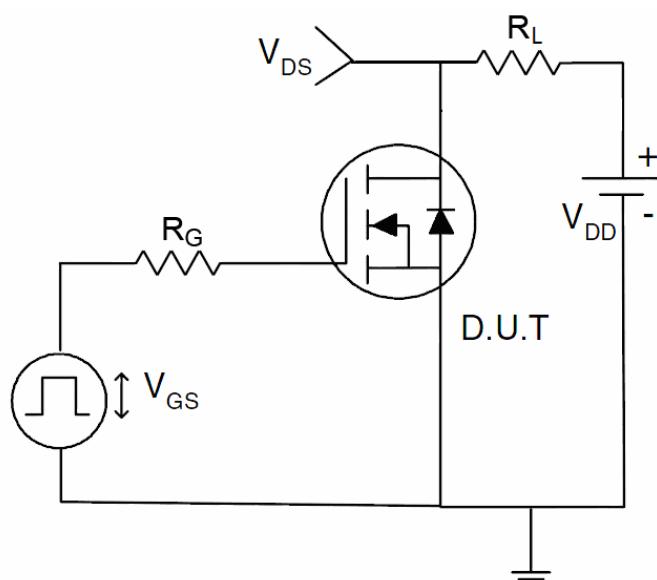
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit



Typical Characteristics

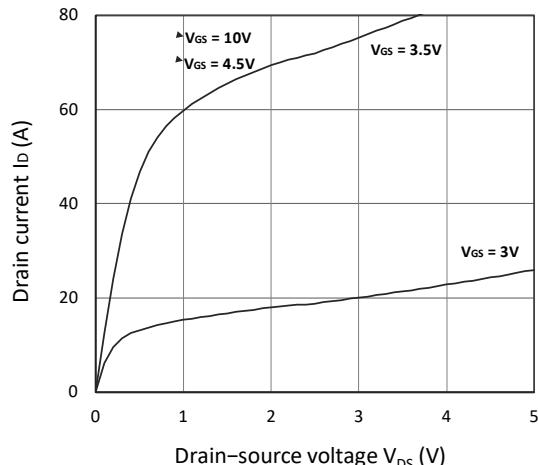


Figure 1. Output Characteristics

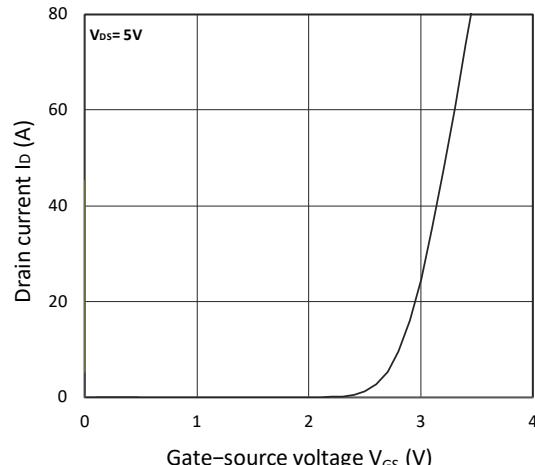


Figure 2. Transfer Characteristics

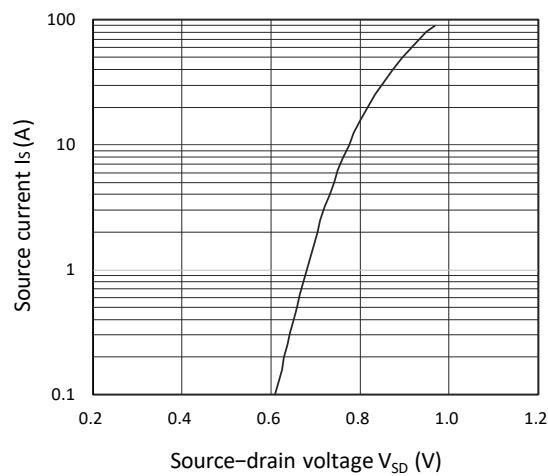


Figure 3. Forward Characteristics of Reverse

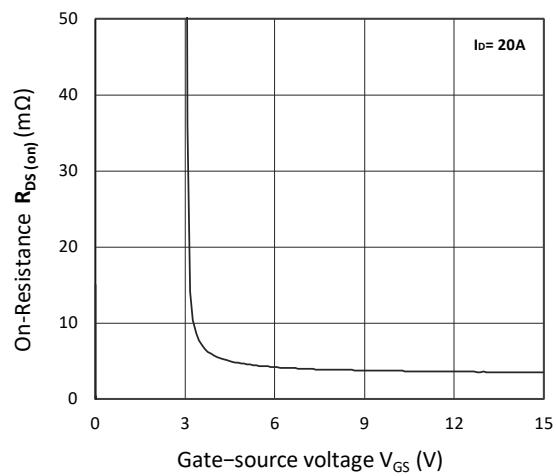


Figure 4. $R_{DS(on)}$ vs. V_{GS}

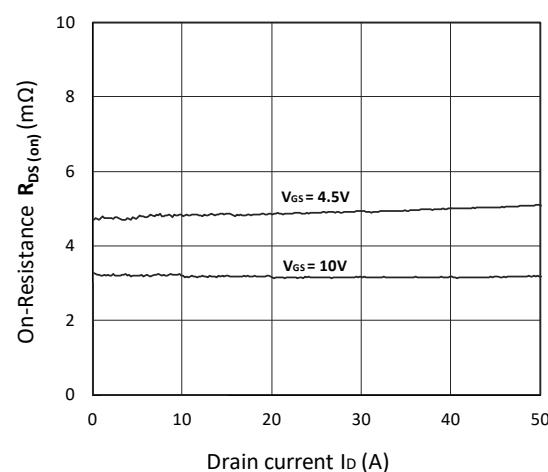


Figure 5. $R_{DS(on)}$ vs. I_D

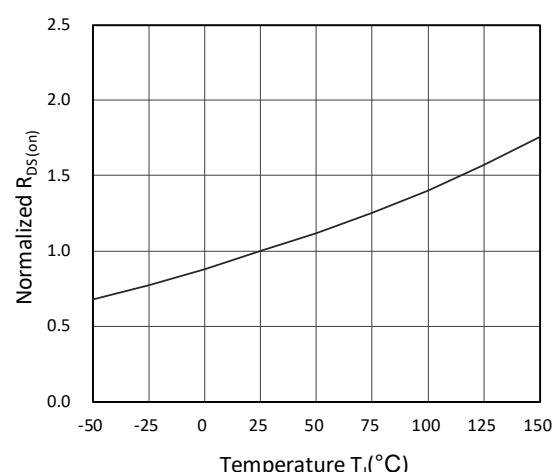


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

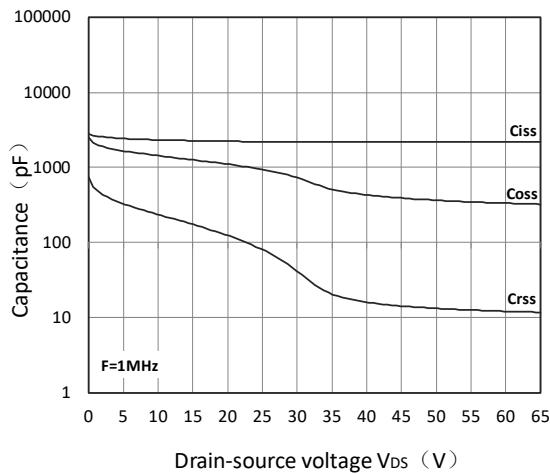


Figure 7. Capacitance Characteristics

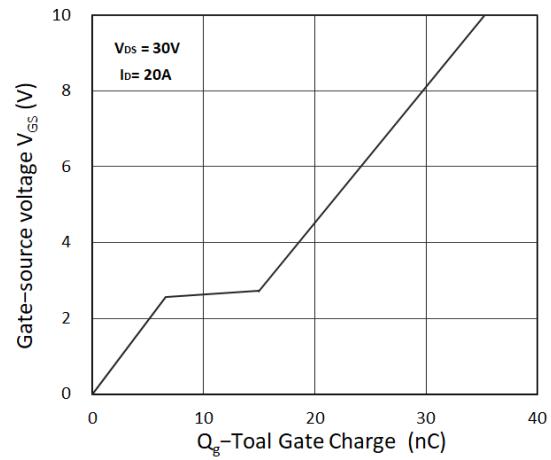


Figure 8. Gate Charge Characteristics

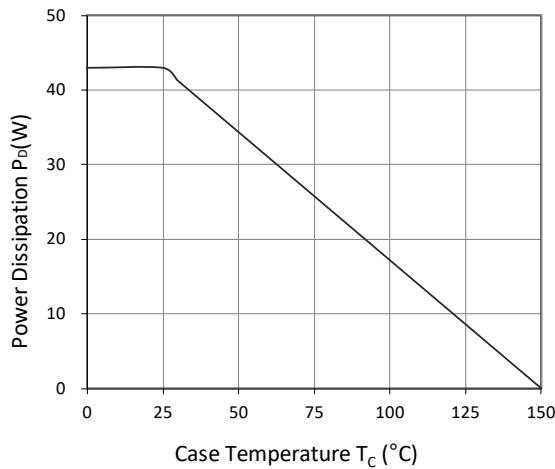


Figure 9. Power Dissipation

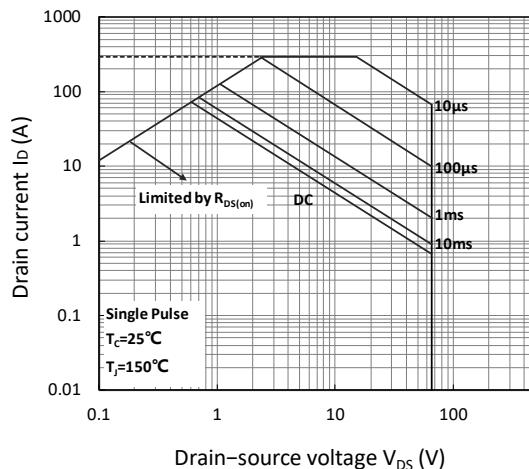


Figure 10. Safe Operating Area

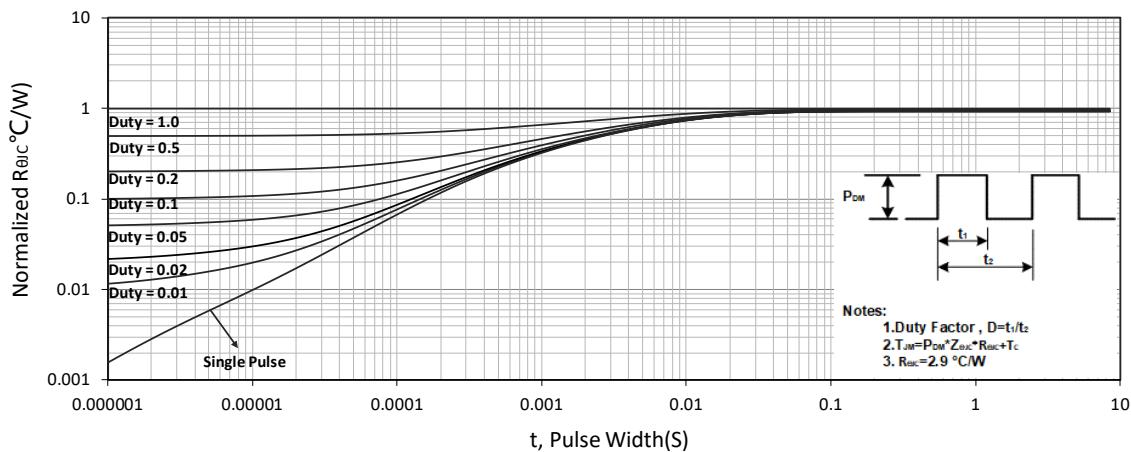


Figure 11. Normalized Maximum Transient Thermal Impedance



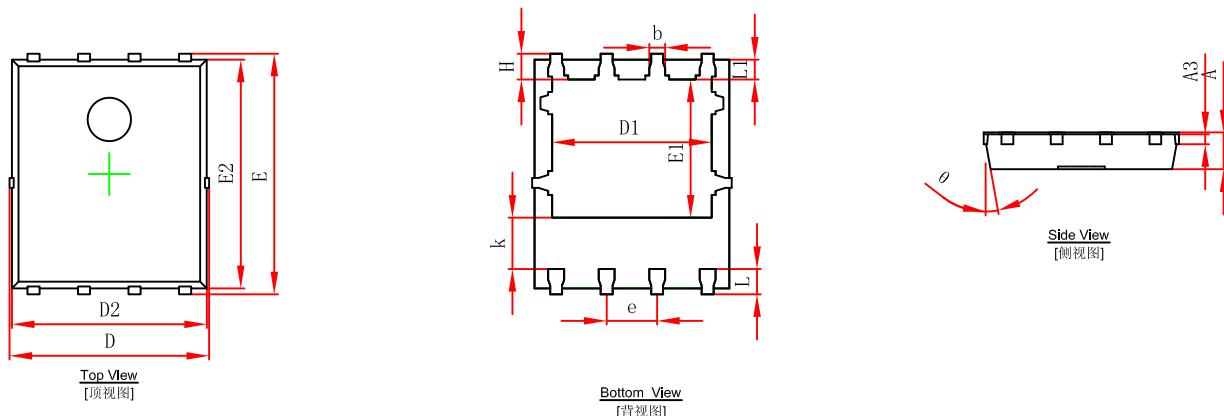
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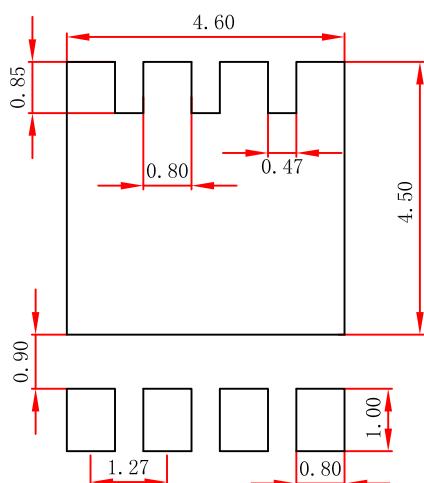
TF030N06NG

PDFNWB5x6-8L Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

PDFNWB5x6-8L Suggested Pad Layout



Note:

1. Controlling dimension:in millimeters.
2. General tolerance: $\pm 0.05\text{mm}$.
3. The pad layout is for reference purposes only.